## High Speed PT IGBT

POWER MOS $8^{\circledR}$ is a high speed Punch-Through switch-mode IGBT. Low $E_{\text {off }}$ is achieved through leading technology silicon design and lifetime control processes. A reduced $\mathrm{E}_{\text {off }}$ $\mathrm{V}_{\mathrm{CE}(\mathrm{ON})}$ tradeoff results in superior efficiency compared to other IGBT technologies. Low gate charge and a greatly reduced ratio of $\mathrm{C}_{\text {res }} / \mathrm{C}_{\text {ies }}$ provide excellent noise immunity, short delay times and simple gate drive. The intrinsic chip gate resistance and capacitance of the poly-silicone gate structure help control di/dt during switching, resulting in low EMI, even when switching at high frequency.


## FEATURES

- Fast switching with low EMI
- Very Low $\mathrm{E}_{\text {off }}$ for maximum efficiency
- Ultra low $\mathrm{C}_{\text {res }}$ for improved noise immunity
- Low conduction loss
- Low gate charge
- Increased intrinsic gate resistance for low EMI
- RoHS compliant


## TYPICAL APPLICATIONS

- ZVS phase shifted and other full bridge
- Half bridge
- High power PFC boost
- Welding
- UPS, solar, and other inverters
- High frequency, high efficiency industrial


## Absolute Maximum Ratings

| Symbol | Parameter | Ratings | Unit |
| :---: | :---: | :---: | :---: |
| $V_{\text {ces }}$ | Collector Emitter Voltage | 900 | V |
| $\mathrm{I}_{\mathrm{C} 1}$ | Continuous Collector Current @ $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 48 | A |
| $\mathrm{I}_{\mathrm{C} 2}$ | Continuous Collector Current @ $\mathrm{T}_{\mathrm{C}}=100^{\circ} \mathrm{C}$ | 27 |  |
| $\mathrm{I}_{\text {CM }}$ | Pulsed Collector Current ${ }^{1}$ | 79 |  |
| $V_{G E}$ | Gate-Emitter Voltage ${ }^{2}$ | $\pm 30$ | V |
| $\mathrm{P}_{\mathrm{D}}$ | Total Power Dissipation @ $\mathrm{C}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 223 | W |
| SSOA | Switching Safe Operating Area @ $\mathrm{T}_{\mathrm{J}}=150^{\circ} \mathrm{C}$ | 79A @ 900V |  |
| $\mathrm{T}_{\mathrm{J},}, \mathrm{T}_{\text {STG }}$ | Operating and Storage Junction Temperature Range | -55 to 150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{L}}$ | Lead Temperature for Soldering: 0.063" from Case for 10 Seconds | 300 |  |

Static Characteristics
$\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$ unless otherwise speci fied

| Symbol | Parameter | Test Conditions |  | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {BR(CES }}$ | Collector-Emitter Breakdown Voltage | $\mathrm{V}_{\mathrm{GE}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{C}}=1.0 \mathrm{~mA}$ |  | 900 |  |  | V |
| $V_{\text {cE(on) }}$ | Collector-Emitter On Voltage | $\begin{gathered} \mathrm{V}_{\mathrm{GE}}=15 \mathrm{~V}, \\ \mathrm{I}_{\mathrm{C}}=14 \mathrm{~A} \end{gathered}$ | $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$ |  | 2.5 | 3.1 |  |
|  |  |  | $\mathrm{T}_{\mathrm{J}}=125^{\circ} \mathrm{C}$ |  | 2.2 |  |  |
| $\mathrm{V}_{\text {GE(th) }}$ | Gate Emitter Threshold Voltage | $\mathrm{V}_{G E}=\mathrm{V}_{\text {CE }}, \mathrm{I}_{\mathrm{C}}=1 \mathrm{~mA}$ |  | 3 | 4.5 | 6 |  |
| $\mathrm{I}_{\text {ces }}$ | Zero Gate Voltage Collector Current | $\mathrm{V}_{\text {CE }}=900 \mathrm{~V}$, | $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$ |  |  | 250 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\text {GE }}=0 \mathrm{~V}$ | $\mathrm{T}_{\mathrm{J}}=125^{\circ} \mathrm{C}$ |  |  | 2500 |  |
| $\mathrm{I}_{\text {GES }}$ | Gate-Emitter Leakage Current | $\mathrm{V}_{\mathrm{GS}}= \pm 30 \mathrm{~V}$ |  |  |  | $\pm 100$ | nA |

## Thermal and Mechanical Characteristics

| Symbol | Characteristic | Min | Typ |
| :---: | :--- | :---: | :---: |
| $R_{\text {өлс }}$ | Junction to Case Thermal Resistance | - | - |
| $\mathrm{W}_{\mathrm{T}}$ | Package Weight | - | 0.56 |
| Torque | Mounting Torque (TO-220 Package), 4-40 or M3 screw | - | 1.9 |
| ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |  |  |  |



1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
2 Pulse test: Pulse Width < $380 \mu$ s, duty cycle $<2 \%$.
3 See Mil-Std-750 Method 3471.
$4 R_{G}$ is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)
$5 \mathrm{E}_{\text {on2 }}$ is the clamped inductive turn on energy that includes a commutating diode reverse recovery current in the IGBT turn on energy loss. A combi device is used for the clamping diode.
$6 E_{\text {off }}$ is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1.
Microsemi reserves the right to change, without notice, the specifications and information contained herein.

TO-220 (K) Package Outline


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[^0]:    Microsemi's products are covered by one or more of U.S. patents 4,895,810 5,045,903 5,089,434 5,182,234 5,019,522 5,262,336 6,503,786 5,256,583 4,748,103 5,283,202 5,231,474 5,434,095 5,528,058 6,939,743, 7,352,045 5,283,201 5,801,417 5,648,283 7,196,634 6,664,594 7,157,886 6,939,743 7,342,262 and foreign patents. US and Foreign patents pending. All Rights Reserved.

